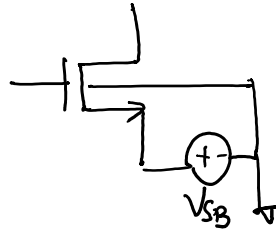
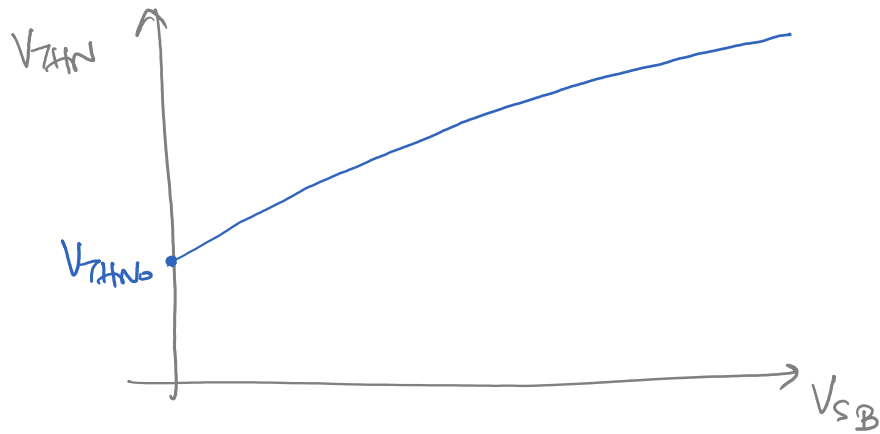
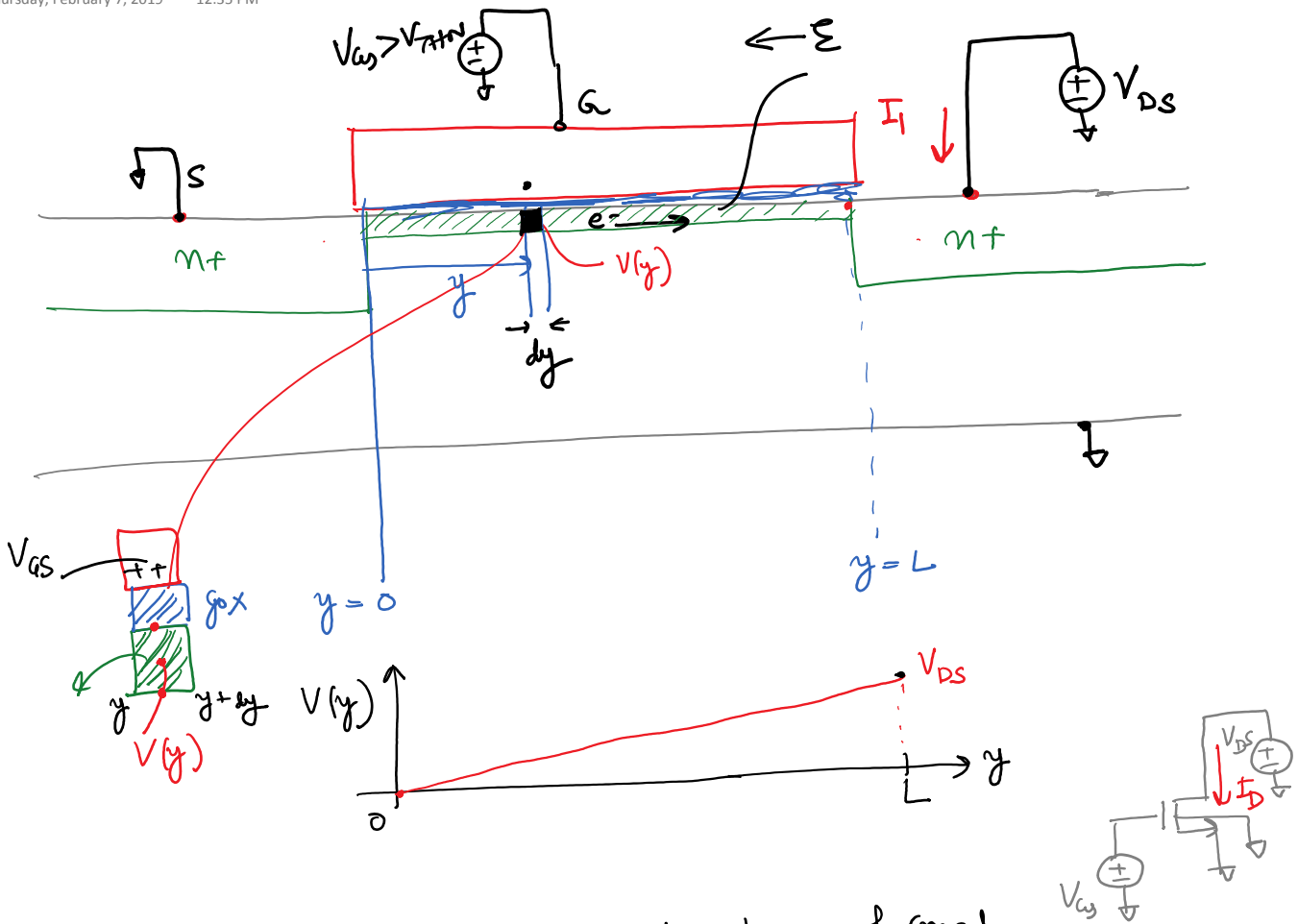


I-V characteristics of MOSFETs

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$$V_{THN} = V_{THN0} + \gamma (\sqrt{|2V_{fp}| + V_{SB}} - \sqrt{|2V_{fp}|})$$





potential across the tiny capacitance formed by the gate and the segment of inversion layer
 $= V_{GS} - V(y)$

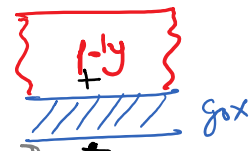
charge per unit area in the inversion layer

$$Q'_{ch} = C_{ox} [V_{GS} - V(y)] \quad \text{--- (1)}$$

We also know that the charge Q'_0 present in the inversion layer from the application of threshold voltage

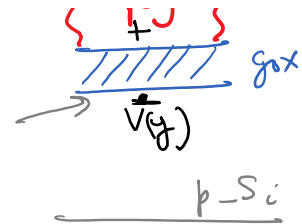
$$Q'_0 = C_{ox} V_{THN} \quad \text{--- (2)}$$

same



Total inversion layer charge

$$Q'_I(y) = C_{ox} (V_{GS} - V(y) - V_{THN})$$



③

charge per unit area = $Q'_I(y)$

Conductivity of the channel

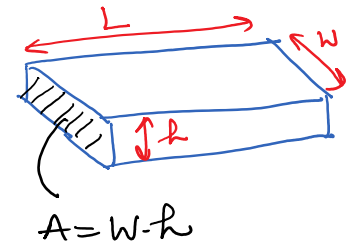
$$\sigma = nq\mu_n$$

$1.6 \times 10^{-19} \text{ C}$
 electron concentration p.u. volume
 mobility of electron

electron concentration p.u. volume

$$= \frac{Q'_I}{h} \mu_n$$

charge p.u. area



$$\sigma = \frac{Q'_I(y)}{h} \mu_n$$

resistivity

$$\rho = \frac{1}{\sigma} = \frac{h}{\mu_n Q'_I(y)}$$

$$R = \rho \frac{L}{A}$$

$$dR = \rho(y) \cdot \frac{dy}{A} = \rho(y) \frac{dy}{W \cdot h}$$

$$= \frac{h}{\mu_n Q'_I(y)} \cdot \frac{dy}{W \cdot h}$$

$$dR = \frac{1}{\mu_n Q'_I(y)} \cdot \frac{dy}{W} \longrightarrow \textcircled{4}$$

$$\mu_n Q'_E(y) \cdot W$$

$$dV(y) = \frac{I_D}{W \mu_n Q'_E(y)} \cdot dy \quad \because V = IR \quad \text{--- (5)}$$

Substituting eqⁿ (3) into (5) we get

$$dV(y) = \frac{I_D \cdot dy}{W \mu_n C_{ox} (V_{GS} - V(y) - V_{THN})}$$

$$\Rightarrow I_D \cdot dy = W \mu_n C_{ox} [V_{GS} - V(y) - V_{THN}] \cdot dV(y) \quad \text{--- (6)}$$

Let's define parameters

Transconductance parameter $\rightarrow$

$$K_{Pn} = \mu_n C_{ox} = \mu_n \frac{C_{ox}}{L} = 120 \frac{\mu A}{V^2}$$

$$K_{Pp} = \mu_p C_{ox} = \mu_p \frac{C_{ox}}{L} = 40 \frac{\mu A}{V^2}$$

in $1 \mu m$ CMOS

$$\frac{K_{Pn}}{K_{Pp}} = \frac{\mu_n}{\mu_p} \approx 3 \quad \text{in long-channel CMOS}$$

$$I_D \int_0^L dy = W \cdot K_{Pn} \int_0^{V_{DS}} (V_{GS} - V(y) - V_{THN}) dV(y)$$

$$\Rightarrow I_D = K_{Pn} \cdot \frac{W}{L} \left[(V_{GS} - V_{THN}) \cdot V_{DS} - \frac{V_{DS}^2}{2} \right] \quad \text{--- (7)}$$

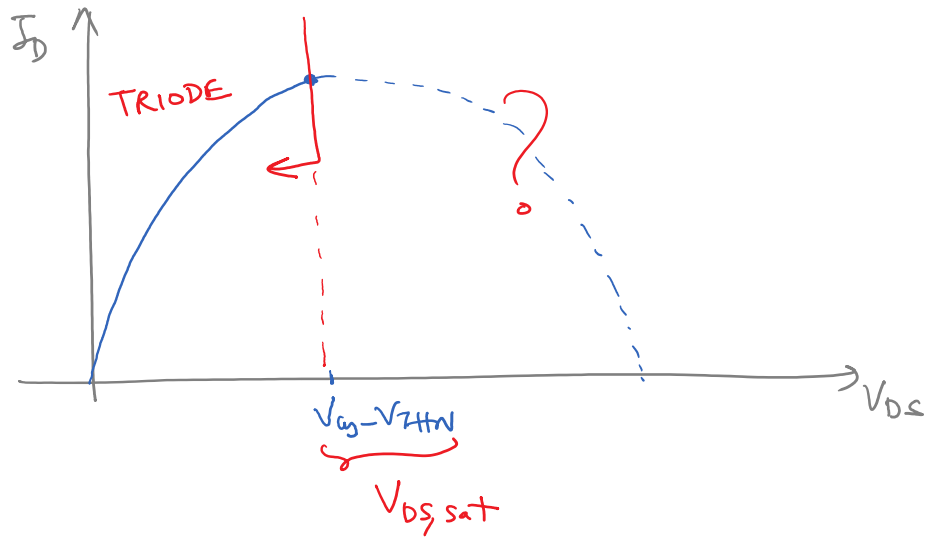
only true for $V_{GS} > V_{THN}$ & $V_{DS} < V_{GS} - V_{THN}$

This equation is only valid for

$V_{DS} < V_{GS} - V_{THN} \Rightarrow$ LINEAR OR TRIODE REGION

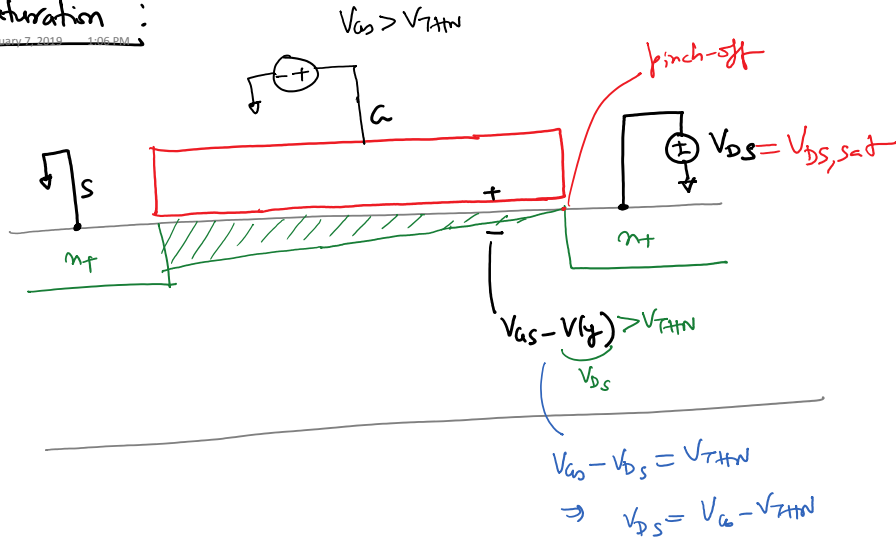
Defn: $\beta_n = K_{Pn} \frac{W}{L}$

Beta: $\beta_n = k\mu_n \frac{W}{L}$



Saturation :

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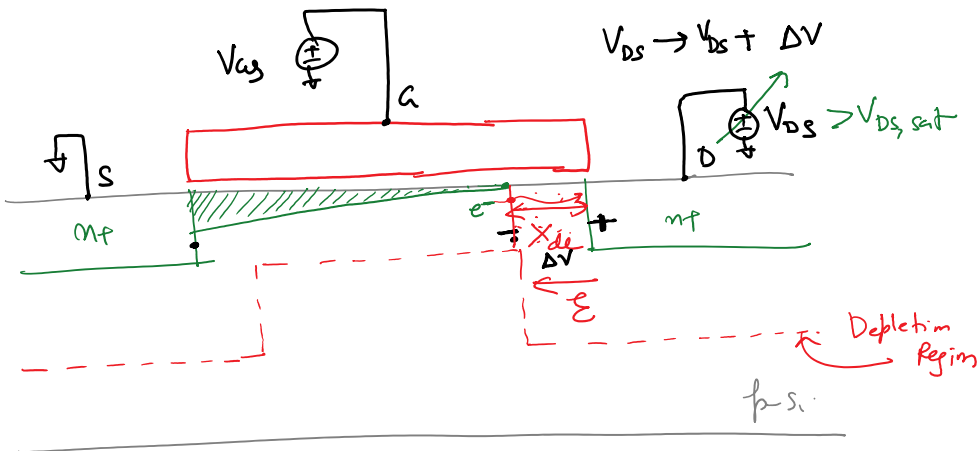


if we have

$$V(y=L) = V_{DS} = \underline{V_{GS} - V_{TN}}_{V_{DS,sat}}$$

$$\Rightarrow Q'(y=L) = 0$$

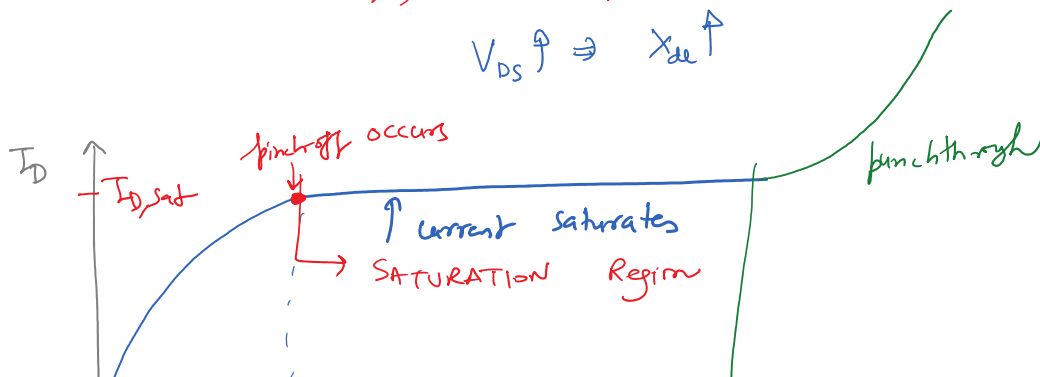
↳ channel is pinched-off at the drain edge.

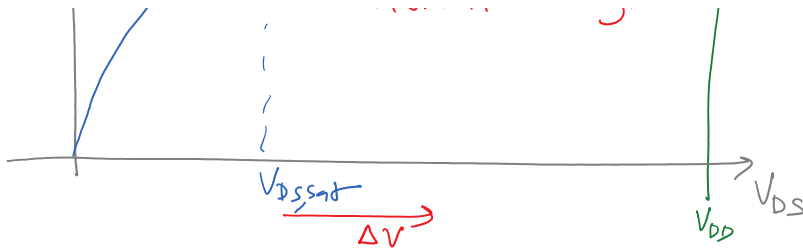


* If we increase V_{DS} beyond $V_{DS,sat}$
 ↳ inversion layer is pushed away from the drain

↳ leaves a depletion region of length x_{de}

$$V_{DS} \uparrow \Rightarrow x_{de} \uparrow$$





- * Beyond pinchoff, any increase in V_{DS} is dropped across the depletion region
 - ↳ voltage across the inversion layer doesn't increase
 - ↳ current doesn't increase beyond the pinchoff current, $I_{D,sat}$

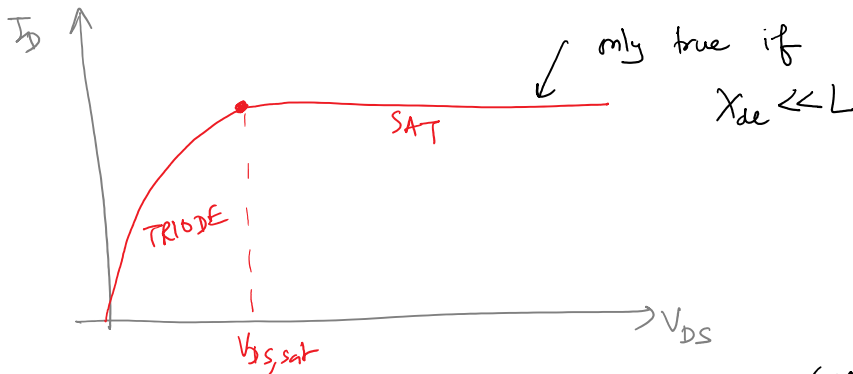
$$I_D = k_n \frac{W}{L} \left[(V_{GS} - V_{THN}) V_{DS} - \frac{V_{DS}^2}{2} \right]$$

In saturation, V_{DS} across the channel = $V_{GS} - V_{THN}$

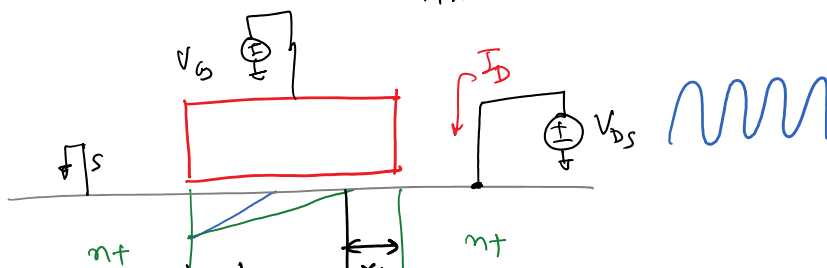
$$I_{D,sat} = k_n \frac{W}{L} \left[(V_{GS} - V_{THN})^2 - \frac{(V_{GS} - V_{THN})^2}{2} \right]$$

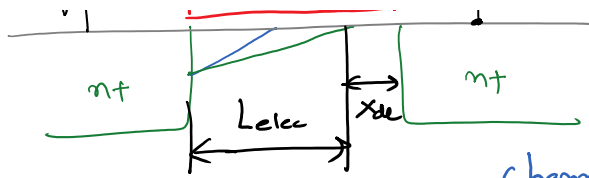
$$I_D = \frac{1}{2} k_n \frac{W}{L} (V_{GS} - V_{THN})^2$$

Saturation
 $V_{DS} > V_{GS} - V_{THN}$



for small lengths $L < 1 \mu m \Rightarrow$ Submicron CMOS
 $14 nm \rightarrow$ nanoscale CMOS





Channel Length Modulation (CLM)

$$L_{elec} = L - x_{de}$$

Current in Saturation

$$I_D = \frac{1}{2} k_p n \frac{W}{L_{elec}} (V_{DS} - V_{THN})^2$$

$$V_{DS} \uparrow \Rightarrow x_{de} \uparrow \Rightarrow L_{elec} \downarrow \Rightarrow I_D \uparrow$$

Taylor's Series approximation of $f(x)$ around $x=x_0$

$$f(x) = f(x_0) + \left. \frac{df}{dx} \right|_{x_0} (x - x_0) + \frac{1}{2!} \left. \frac{d^2f}{dx^2} \right|_{x_0} (x - x_0)^2 + \dots$$

$$I_D(V_{DS}) = I_D(V_{DS,sat}) + \left(\frac{\partial I_D}{\partial V_{DS}} \right) (V_{DS} - V_{DS,sat}) + \dots$$

$$\begin{aligned} \frac{\partial I_D}{\partial V_{DS}} &= -\frac{k_p n}{2} \frac{W}{L_{elec}} (V_{DS} - V_{THN})^2 \cdot \frac{\partial L_{elec}}{\partial V_{DS}} \\ &= I_D \cdot \left[\frac{1}{L_{elec}(V_{DS,sat})} \cdot \frac{\partial x_{de}}{\partial V_{DS}} \right] \end{aligned}$$

$\lambda \Rightarrow$ Channel length modulation parameter

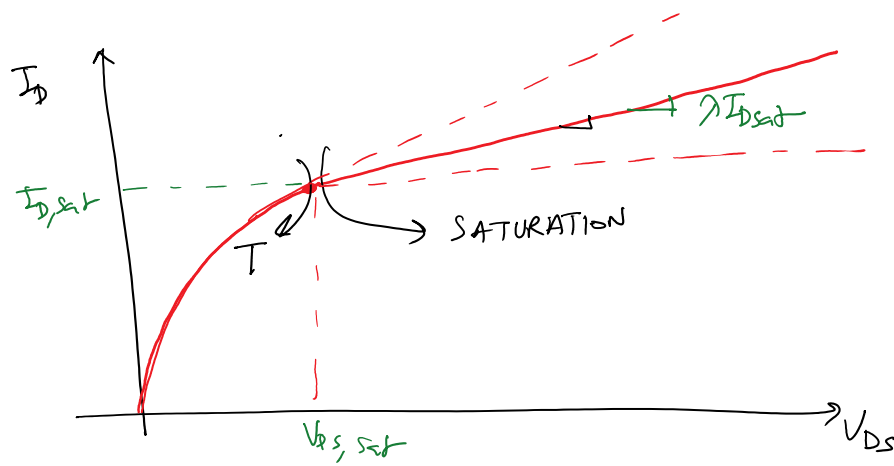
$$I_D = \frac{k_p n}{2} \frac{W}{L} (V_{DS} - V_{THN})^2 \cdot [1 + \lambda (V_{DS} - V_{DS,sat})]$$

Some books

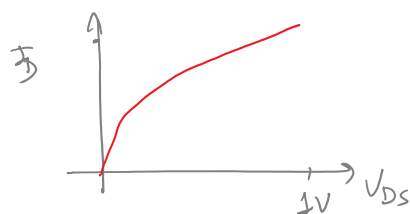
$$I_D = \frac{k_p n}{2} \frac{W}{L} (V_{DS} - V_{THN})^2 \cdot (1 + \lambda V_{DS})$$

$I_D \uparrow$

~~1.2.1.~~



$$r_o = \left(\frac{\partial I_D}{\partial V_{DS}} \right)^{-1} = \frac{1}{\lambda I_{D,sat}}$$



CUTOFF

$$I_D = \begin{cases} 0, & V_{GS} < V_{THN} \\ k_n \mu_n \frac{W}{L} \left[(V_{GS} - V_{THN})V_{DS} - \frac{V_{DS}^2}{2} \right], & V_{GS} > V_{THN} \text{ and } V_{DS} < V_{GS} - V_{THN} \\ \frac{1}{2} k_n \mu_n \frac{W}{L} (V_{GS} - V_{THN})^2 \cdot [1 + \lambda(V_{DS} - V_{DS,sat})], & V_{GS} > V_{THN} \text{ and } V_{DS} > V_{GS} - V_{THN} \end{cases}$$

$V_{DS} < V_{GS} - V_{THN}$, $V_{GS} > V_{THN}$
TRIODE

$V_{DS} > V_{GS} - V_{THN}$ & $V_{GS} > V_{THN}$
SATURATION

